

parent case

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2393		PRIORITY SERIAL NO. 09/592,604	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Fernando Gonzalez		10/659,596	
				PRIORITY FILING DATE June 12, 2000		PRIORITY GROUP 2818	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TL	AA	5,798,649	03/94	Kikuchi	—	—	—
	AB	5,374,564	12/94	Bruehl	—	—	—
	AC	5,855,693	01/99	Murri et al.	—	—	—
	AD	5,877,070	03/99	Goesch et al.	—	—	—
	AE	5,882,987	03/99	Srikrishnan	—	—	—
	AF	5,894,152	04/99	Jaso et al.	—	—	—
	AG	5,953,622	09/99	Lee et al.	—	—	—
	AH	6,004,406	12/99	Kobayashi et al.	—	—	—
	AI	6,309,945 B1	10/01	Sato et al.	—	—	—
	AJ	6,429,070 B1	08/02	Gonzalez et al.	—	—	—
	AK	6,384,439 B1	05/02	Walker	—	—	—
	AL	6,423,992 B2	07/02	Fukuda, et al.	—	—	—
AL	5,998,847	12/99	Assaderaghi, et al.	—	—	—	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
TL	AR	Göschl, U. et al., "Semiconductor Wafer Bonding: Science, Technology, and Applications", Electrochemical Society Proceedings					
		Vol. 97-36, (©1993), pp. 400-425, 436-445.					
	AS						
EXAMINER				DATE CONSIDERED			
[Signature]				7/22/04			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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EV549570899

Sheet 1 of 1

Form PTO-100

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
M122-2393

SERIAL NO.  
10/639,596

APPLICANT  
Fernando Gonzalez

FILING DATE  
Sept. 9, 2003 (RCE filed herewith)

GROUP  
2818

LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APR. 06 2005

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
IL	AA 6,251,754	06/01	Ohshima et al.	—	—	
IL	AB 6,245,161 ✓	06/01	Henley et al.	—	—	
IL	AC 5,374,581	12/94	Ichikawa et al.	—	—	
IL	AD 4,891,329	01/90	Reisman et al.	—	—	
IL	AE 6,150,031 ✓	11/00	Yonehara	—	—	
IL	AF 6,083,324 ✓	07/00	Henley et al.	—	—	
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
	AM					

FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation	
					Yes	No
AN						
AO						
AP						
AQ						
AR						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AS			
AT			

EXAMINER *Thule* DATE CONSIDERED *7/30/05*

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